



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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PATENT & TRADEMARK OFFICE  
TECHNOLOGY CENTER 2800

Application No. : 10/008,204  
Applicant : Geeng-Chuan Chern et al.  
Filed : December 5, 2001  
TC/A.U. : 2826  
Examiner : Pershelle L. Greene  
Title : METHOD OF FORMING DIFFERENT OXIDE THICKNESS  
FOR HIGH VOLTAGE TRANSISTOR AND MEMORY CELL  
TUNNEL DIELECTRIC

Docket No. : 2102397-991220  
Customer No. : 26379

**CERTIFICATE OF MAILING**

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on July 31, 2003.

GRAY CARY WARE & FREIDENRICH Date: 07/31/03

By: Kathleen LaBrie  
Kathleen LaBrie

**RESPONSE TO OFFICE ACTION OF APRIL 23, 2003**

Sir:

In response to the Office Action of April 23, 2003, please enter the following remarks/arguments for the above identified application:

**The pending Claims** are reflected in the listing of claims which begins on page 2 of this paper.

**Remarks/Arguments** begin on page 6 of this paper.